IACLE meeting at NCC 2020 Sunday, 15 March 2020

General information:

Wim Borst and Henri Eek (both IACLE fellows) have organised an IACLE meeting during the Nederlands Contactlens Congres (NCC conference) in Veldhoven, The Netherlands, which is taking place on Sunday 15 and Monday 16 March 2020.



The topics that will be presented are: 'Student education around patient education' and 'The future of contact lens fittings'. The first topic explores the way we educate our students to communicate important contact lens related messages to their patients, and how this changed over time. The second topic currently represents an important issue in the Netherlands and is also one of the main topics at the NCC to be discussed during several conference sessions.

The meeting will be held on Sunday during the lunch break from 12.30-13.30 in the 'Diezezaal'. Lunch will be served before/during the meeting.

Agenda:

- General Introduction IACLE (Henri Eek) 5 minutes.
- 'Student education around patient education' including discussion (Dr Byki Huntjens FIACLE) 30 minutes
- 'Future of contact lens fittings' including discussion (Wim Borst and Henri Eek) 25 minutes

Discussion around each topic:

Topic 1:

- 1. How do we educate our students to communicate important vision/ health related information to their patients?
- 2. What works well and which messages tend to get lost?

This discussion will be the basis of a Do and Don't fact sheet for contact lens educators to enhance and support communications in teaching clinics.

Topic 2:

- 1. How can we train our students in assessing the fit of contact lenses without the use of trial contact lenses?
- 2. Can fluorescein patterns for assessing lens fit be developed and standardized?
- 3. What would an international, standardised, educational curriculum based on topographical measurements look like?

Educators and IACLE members from all over the world are invited to attend the meeting and to join the discussions. We hope to see you all in Veldhoven!

Kind regards, Wim Borst and Henri Eek